

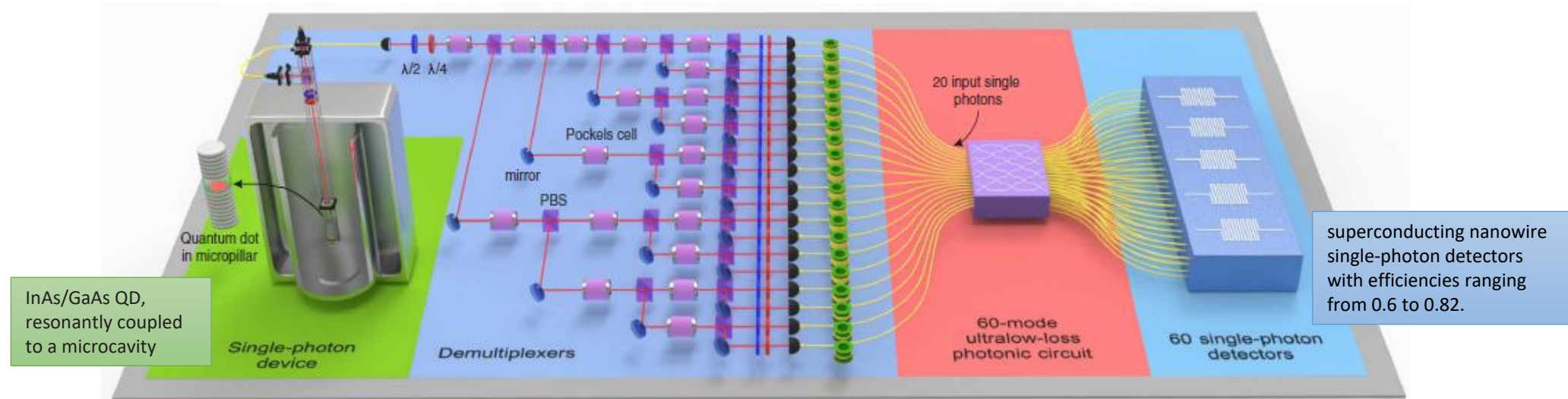
Silicon SPAD monolithically integrated with SiON-based photonic circuit

Fabio Acerbi, Martino Bernard, Alberto Gola, Georg Pucker, Mher Ghulinyan

Fondazione Bruno Kessler (FBK), Center for Sensors and Devices, Trento, Italy.

acerbi@fbk.eu

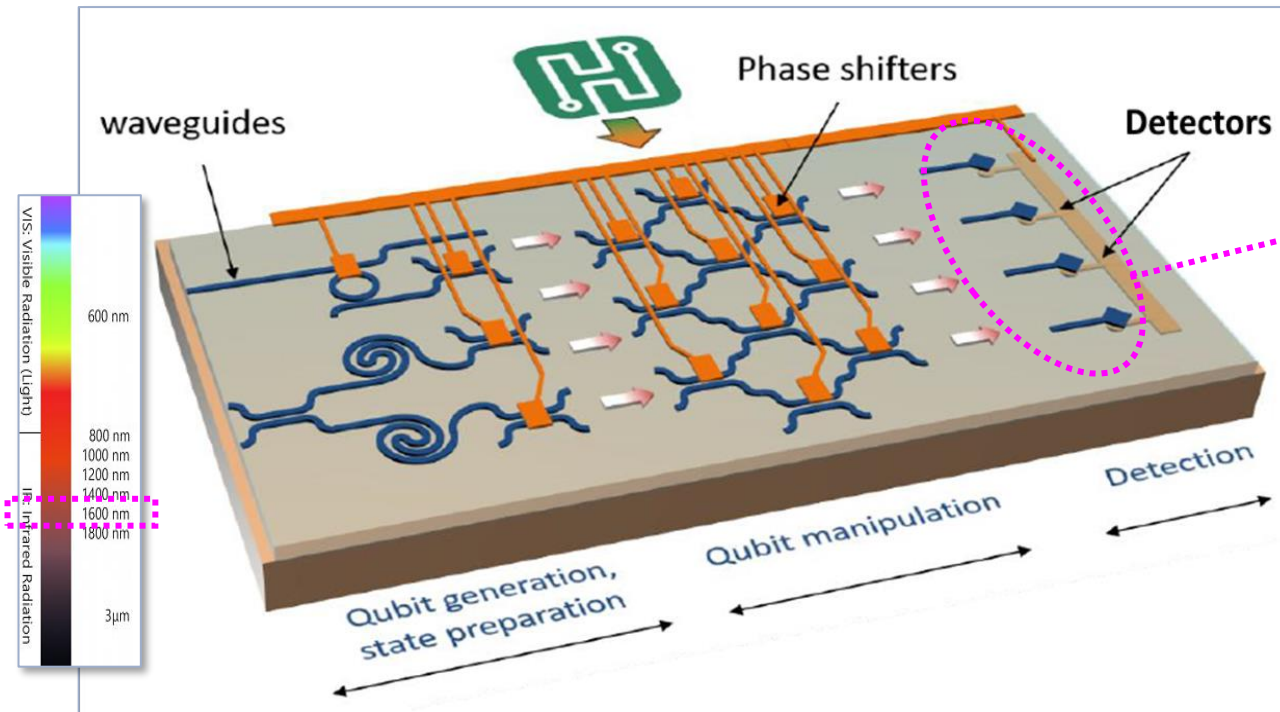
Introduction: Integrated quantum photonic circuits



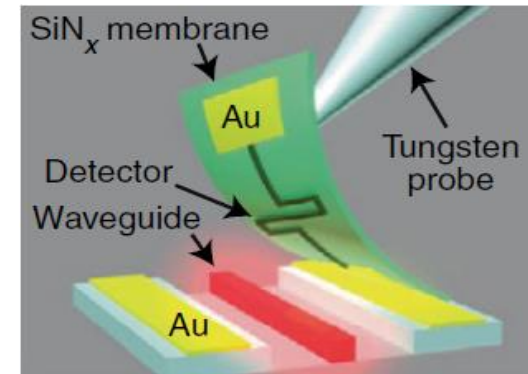
PHYSICAL REVIEW LETTERS 123, 250503 (2019)

- A **breakthrough in quantum photonics** → monolithic **integration** of ph. sources and detectors within quantum PICs.
- Significant interest in this scenario shown by the scientific community for multiple reasons:
 1. Fully exploit all the advantages of the integration, like the unrivaled miniaturization and scalability.
 2. Avoid coupling with external optical fibers and, thus, to guarantee minimal photon losses,
 3. Prompt sensing of a given photonic quantum state thanks to on-chip single photon detection

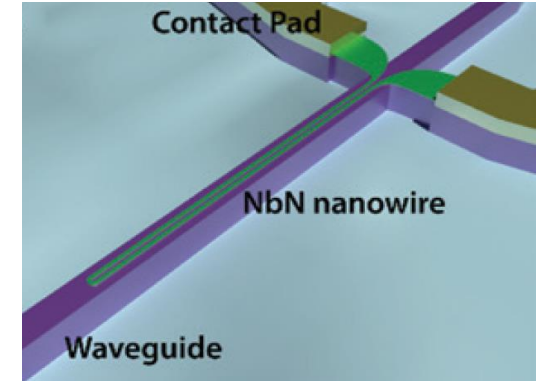
Introduction: Integrated quantum photonic circuits



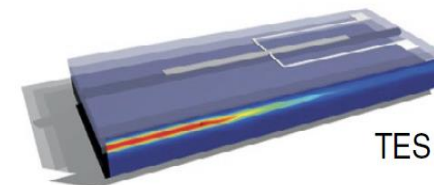
Detector integration in quantum PIC



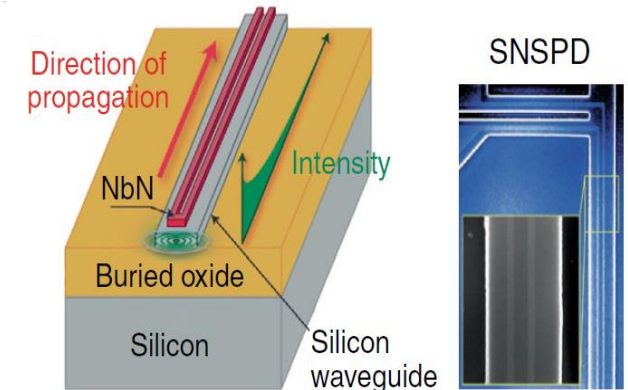
DOI: 10.1038/ncomms6873



Doi: 10.1515/nanoph-2018-0059



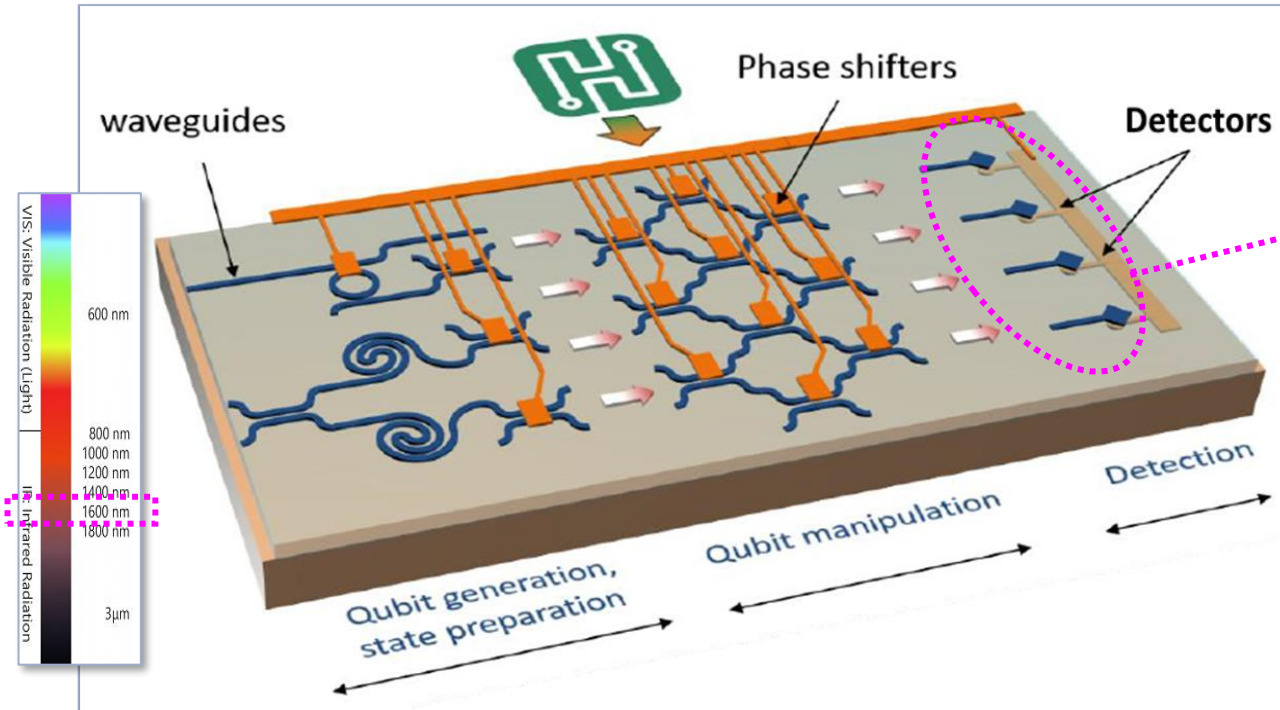
TES



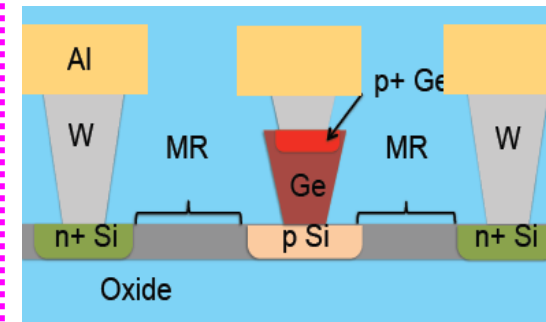
SNSPD

- **Important topic** in quantum photonics → **integration of photon source, manipulation and detection in the PICs.**
- Possible approach:
 1. Si-based photonics (SWIR, e.g. 1550 nm photonics)
 - ❑ PIC integrated with SNSPD or TES: good performance but require cryogenic temperature operation

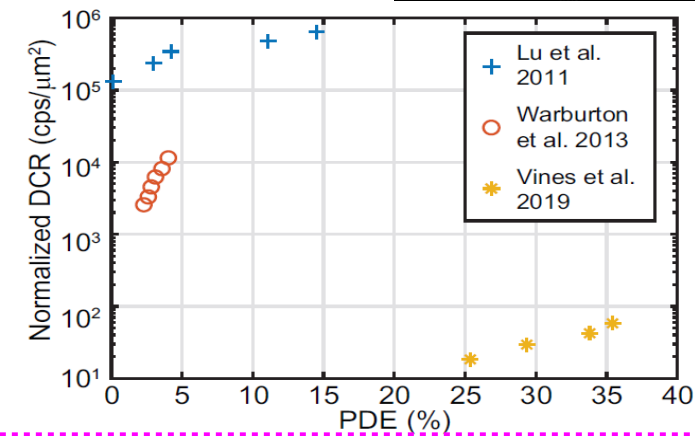
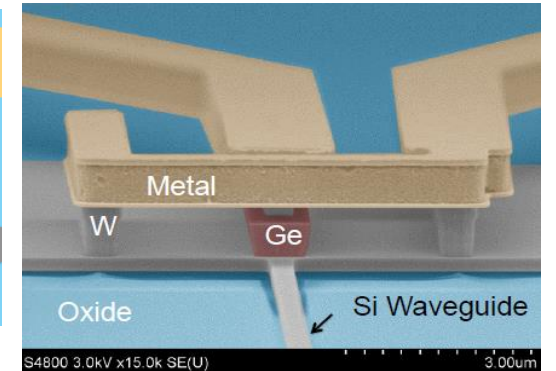
Introduction: Integrated quantum photonic circuits



Detector integration in quantum PIC



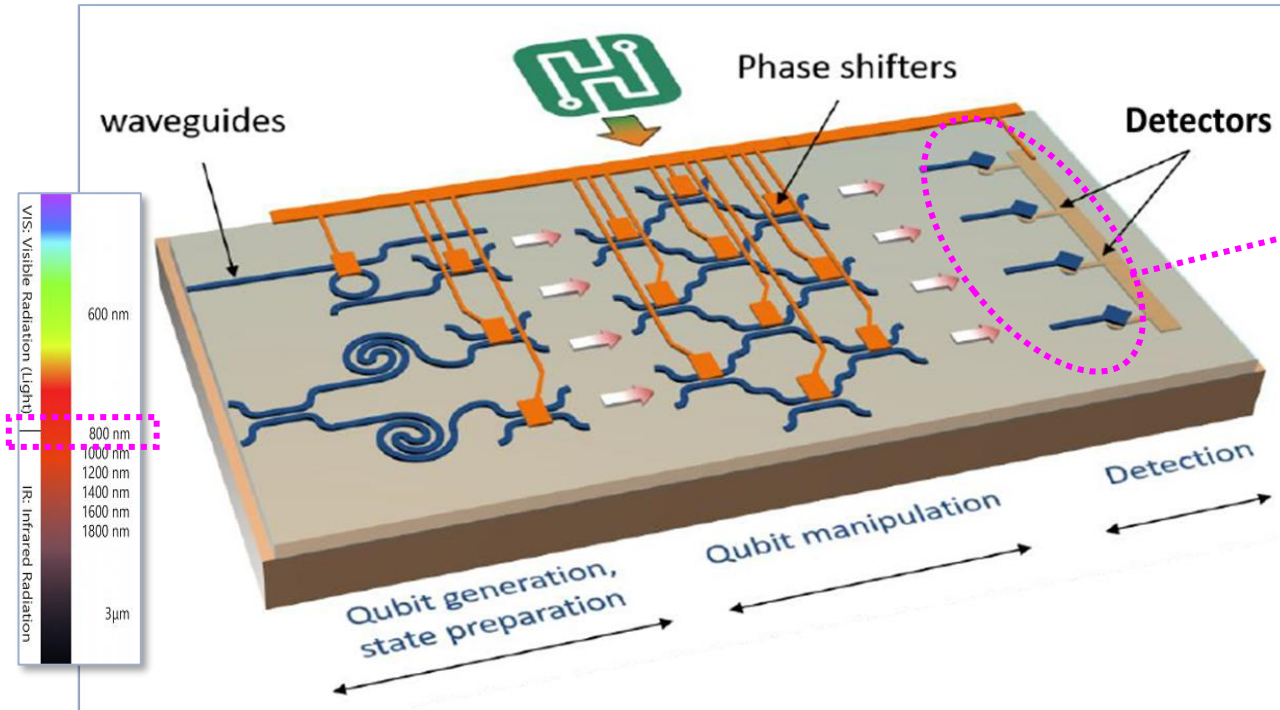
Doi: 10.1364/OE.25.016130



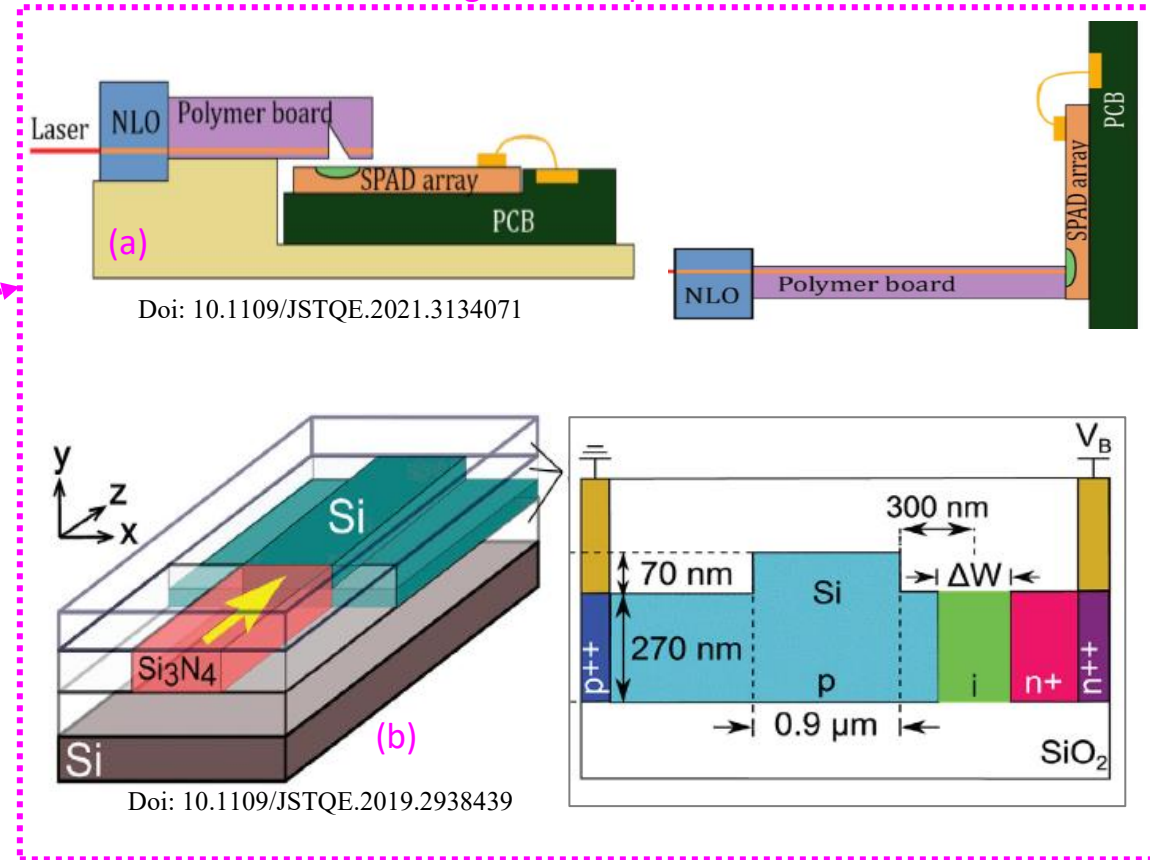
DOI: 10.1002/qute.202000102

- **Important topic** in quantum photonics → **integration of photon source, manipulation and detection in the PICs.**
- Possible approach:
 1. Si-based photonics (SWIR, e.g. 1550 nm photonics)
 - ❑ Ge-on-Si detectors: interesting approach. R&D ongoing but DCR generally very high (even when cooled)

Introduction: Integrated quantum photonic circuits

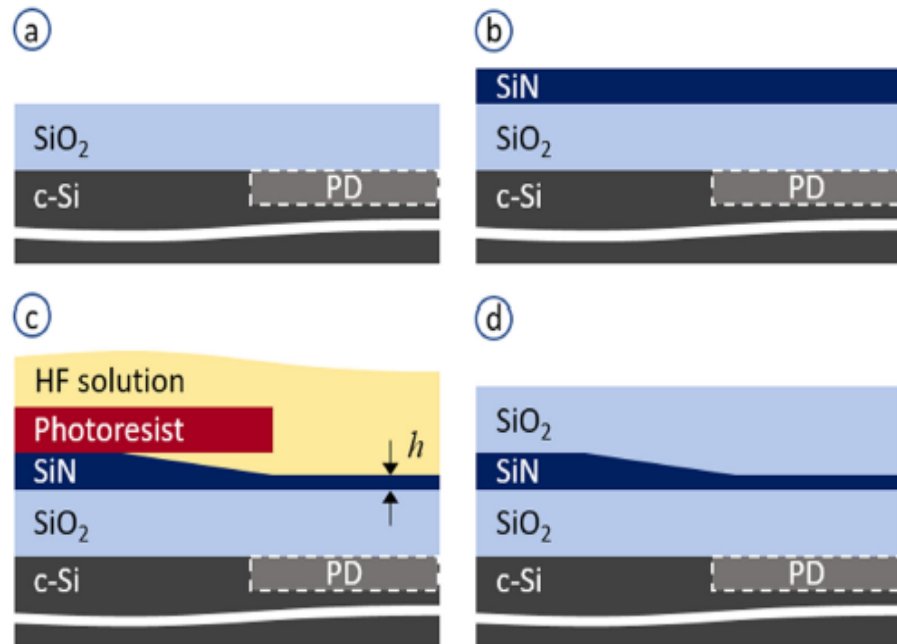


Detector integration in quantum PIC

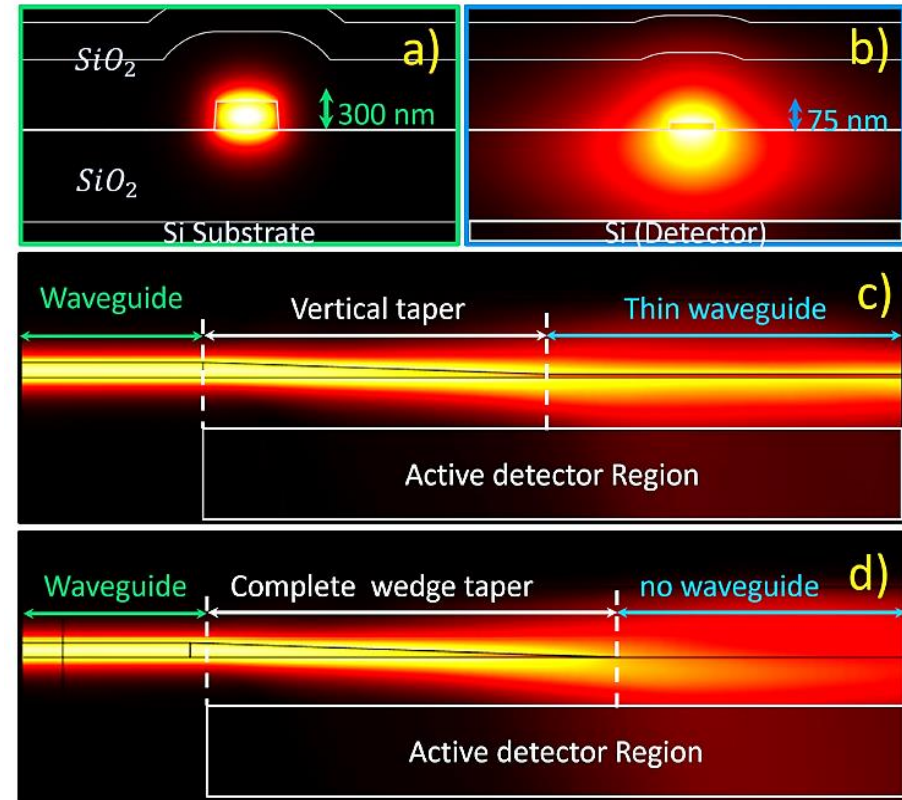


- **Important topic** in quantum photonics → **integration of photon source, manipulation and detection in the PICs.**
- Possible approach:
 2. SiN (or SiON) photonics (NIR photonics, e.g. 850nm)
 - ❑ Silicon-based detectors: (a) system-level integration, or (b) chip-level integration with different materials

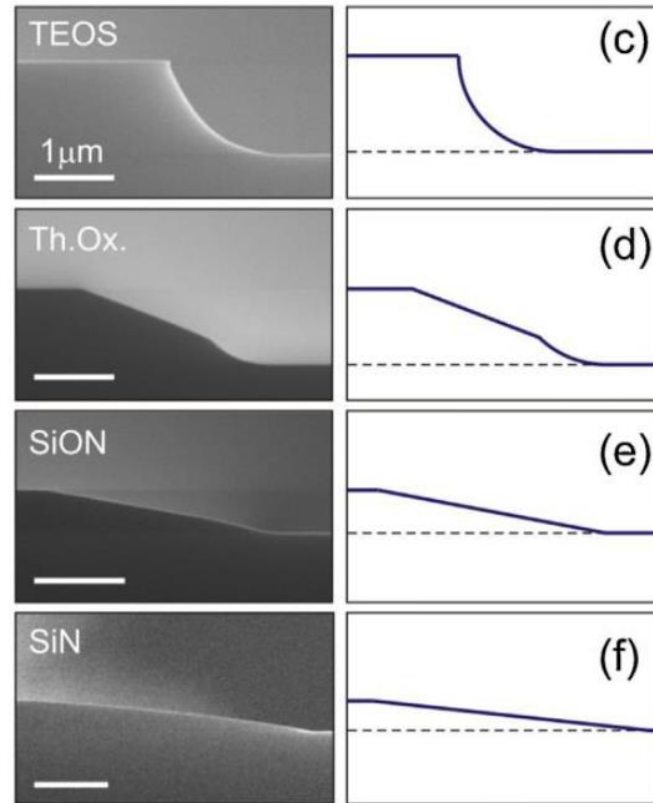
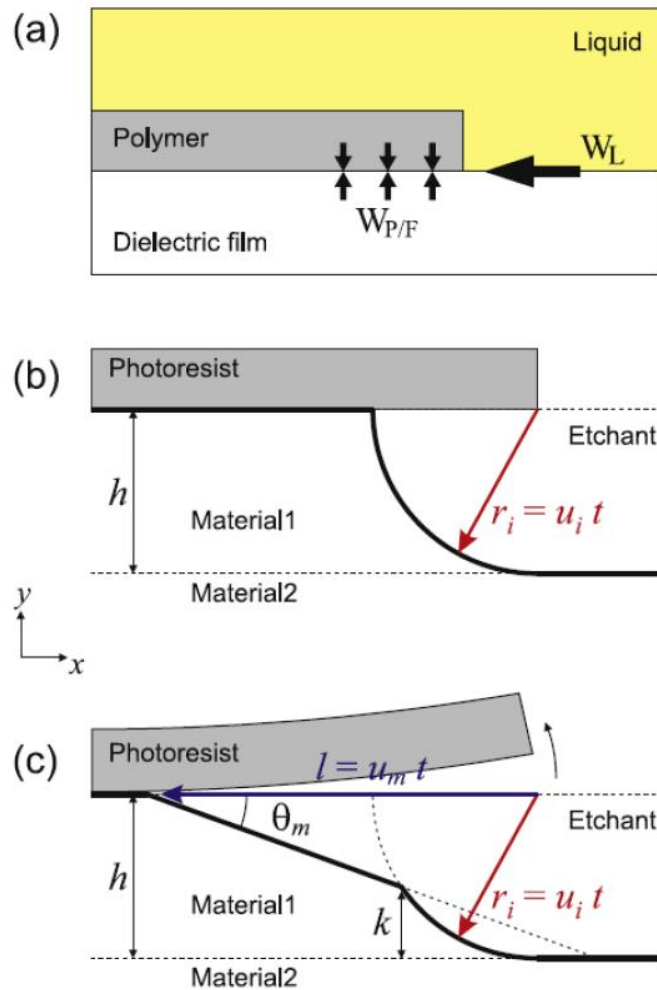
FBK photonic/electronic integration: approach #1



Doi: 10.1109/JLT.2022.3190041



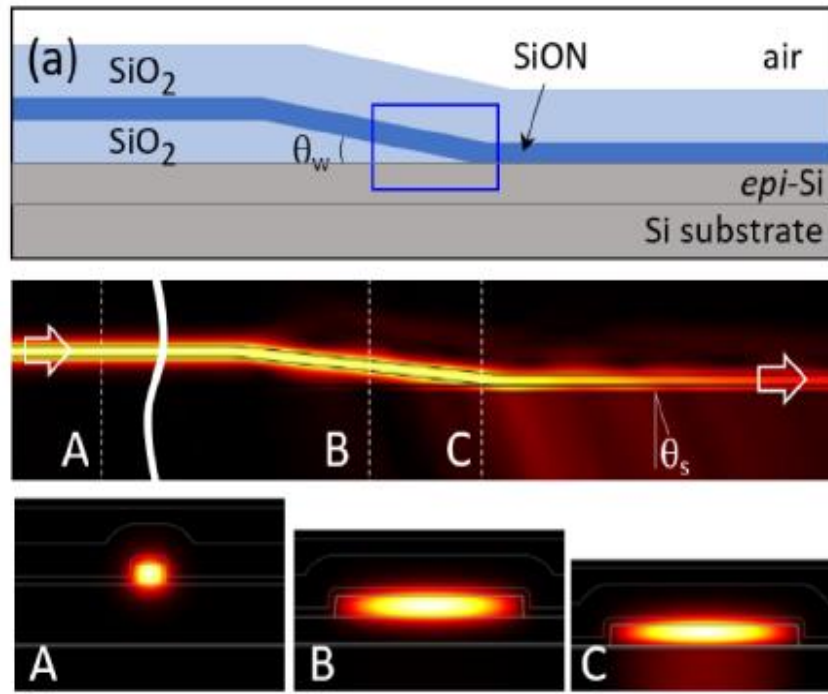
- **Waveguide (PIC) and detector fabricated on the same chip: BEOL region and FEOL region**
- *Approach: customized and precisely-controlled shaping of the waveguide thickness in the detector region*
- *Light is squeezed out of the waveguide, to be detected by the photodiode*



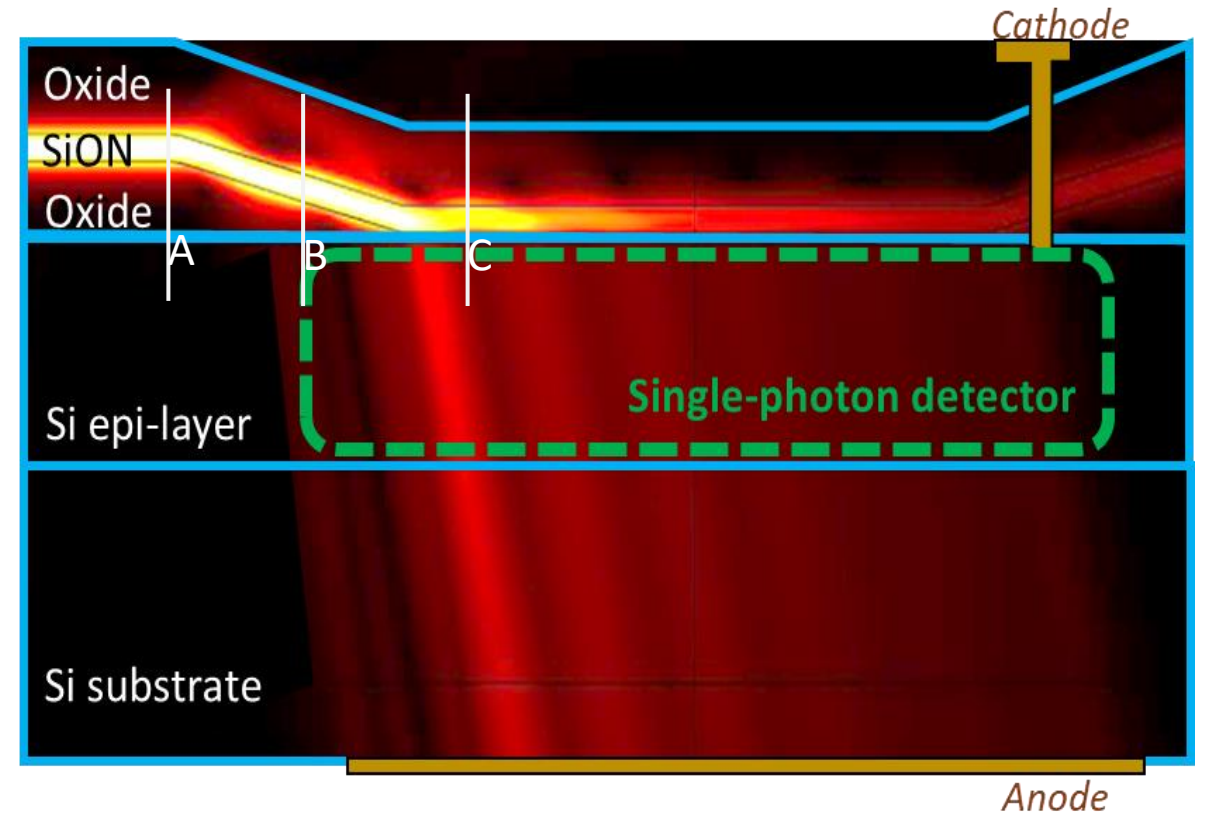
M. Ghulinyan, M. Bernard, R. Bartali, and G. Pucker, Appl. Surf. Sci. 359, 679 (2015).

- the wedge profile is generated by the superposition of the circular isotropic etch fronts, when the peeling (moving object) results into a lateral etching rate u_m , faster than the isotropic one u_i
- Formally, the dynamics of a wedge profile formation is analogous to the formation of a shock wavefront (sonic booms) → the so-called Mach cone.
- Model of the phenomena can be used to precisely-tune and customize the profile.

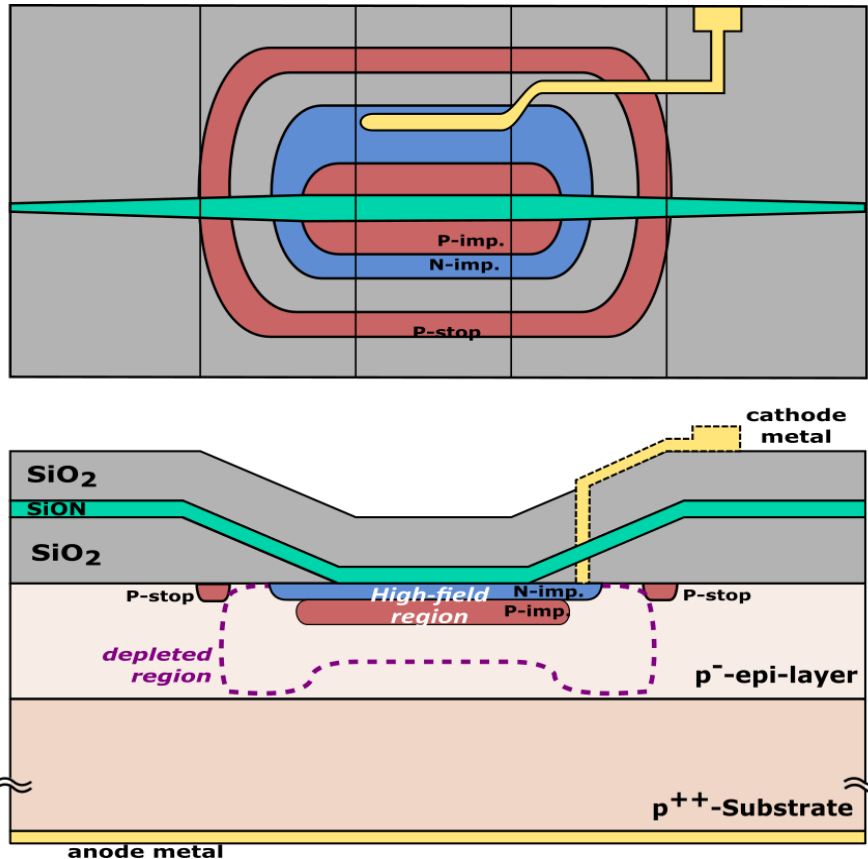
FBK photonic/electronic integration approach #2



Doi: 10.1364/OPTICA.441496



- **Waveguide (PIC) and detector fabricated on the same chip: BEOL region and FEOL region**
- **New efficient top-down evanescent coupling approach (#2)**
 - Precise shaping of the cladding below the Waveguide and of the Waveguide width
 - Efficient evanescent coupling when the WG touches the silicon epi-layer



DOI: 10.1109/JLT.2023.3342031

Novel FBK photonic/electronic integration approach

➤ Advantages:

1. PIC/SPADs can operate at room temperature

- Si-SPADs: with state-of-the-art DCR
- No cooling is needed

2. Completely CMOS compatible

- Material are all already used in CMOS processes (e.g. Silicon, SiO₂, SiNx)

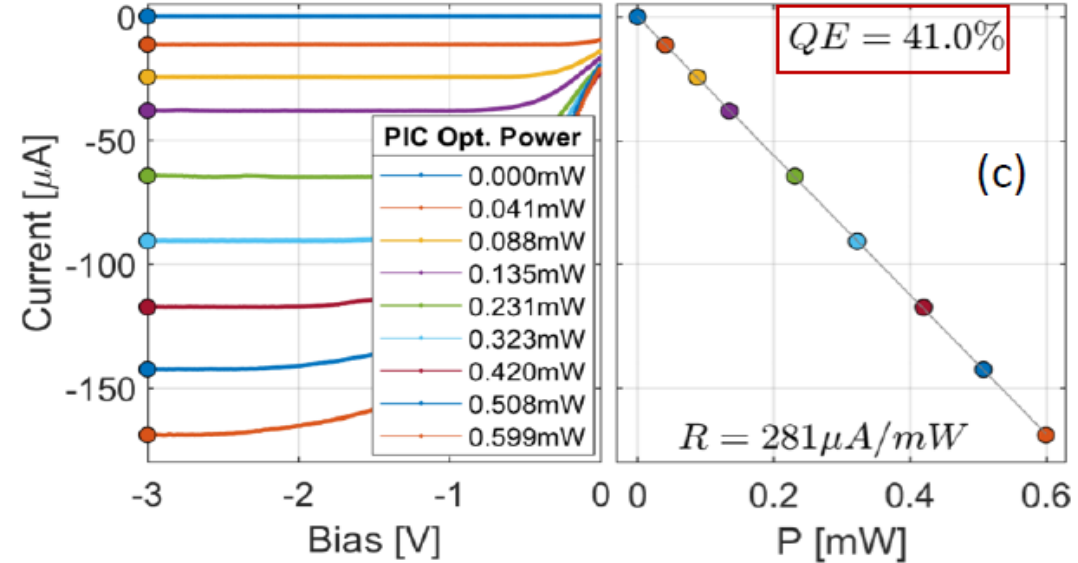
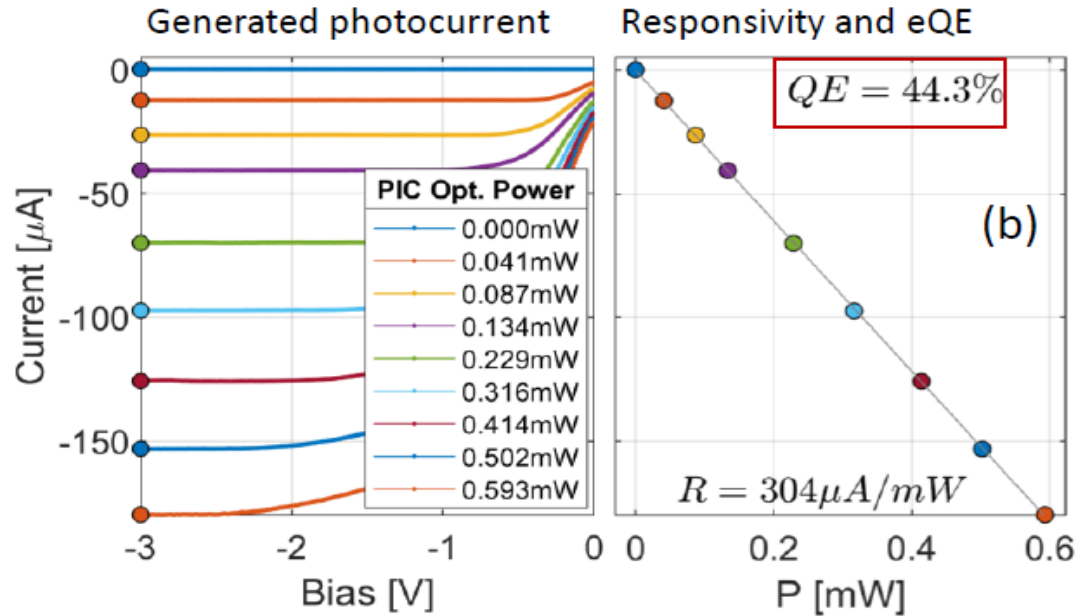
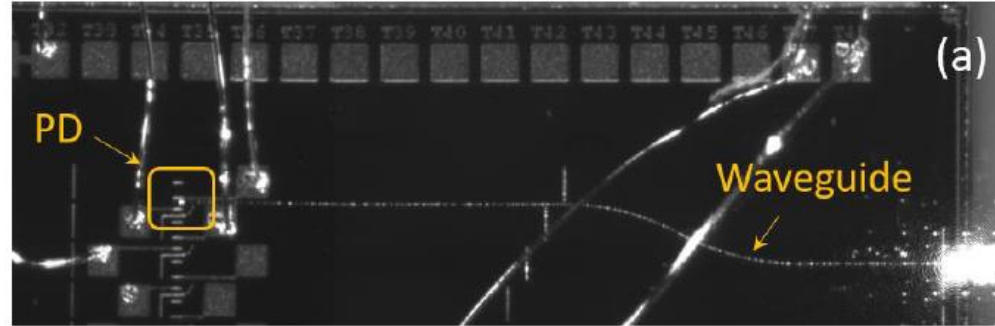
1. Do not require alignments, butt coupling, ...etc...

- *Minimized coupling-losses*
- No complex structures
- No additional materials to be grown / patterned

2. SPAD design: no particular constraints

- Layout of the SPADs tailored for better performances
- No constraint given by the photonic integration

Doi: 10.1364/OPTICA.441496

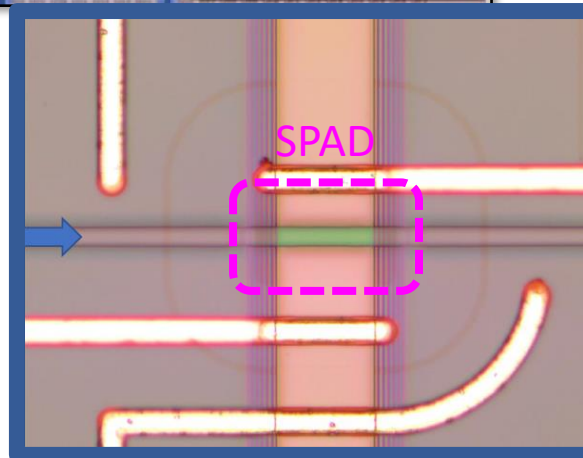
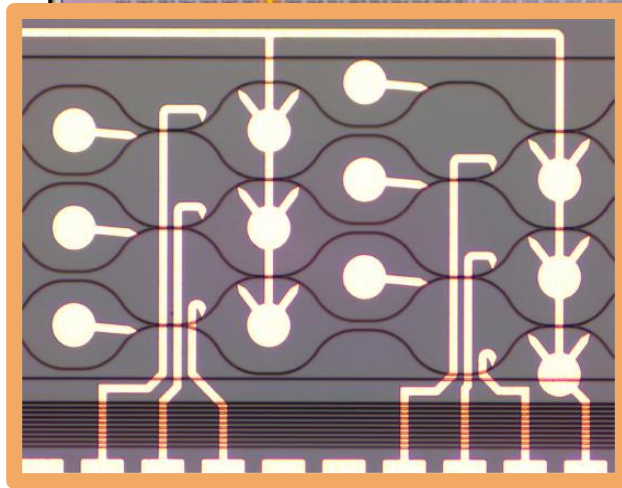
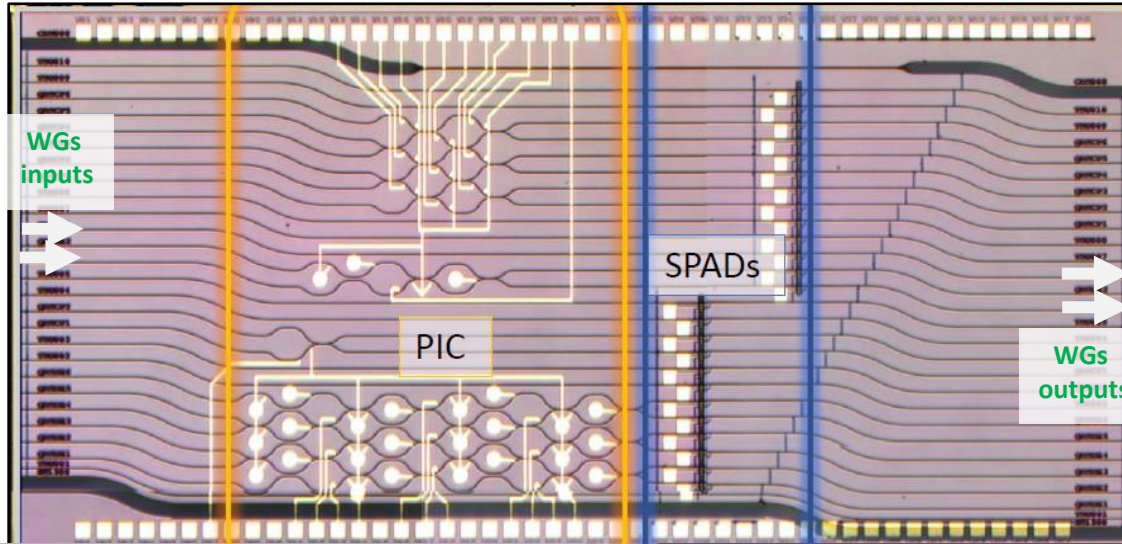


➤ First tests on linear-mode photodiodes

- PIC working in classical-light regime, with moderate light power injected.
- Measured quantum efficiency: $\sim 41 \div 44 \%$

Test chip #1: PIC+SPADs → *photon manipulation and detection*

Test chip: PIC + SPADs (dimensions: 5mm x 10mm)

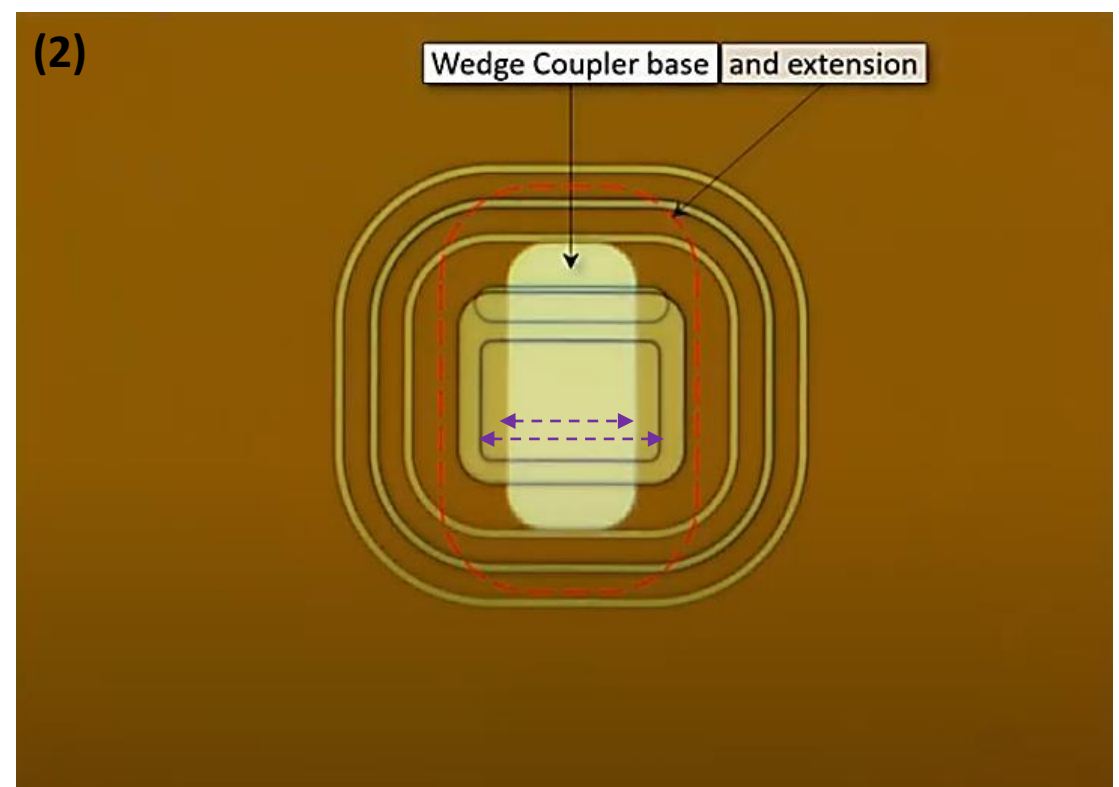


- First implementation of quantum PIC+SPAD
- Several waveguides:
 - Inputs and outputs on opposite facets,
 - Each WG coupled to 1 SPAD
- Manipulation:
 - MZI, based on heaters
- Detection:
 - Si SPADs
 - FBK "RGB" technology (*n-on-p junction type, p-type epi/substrate*)



Grant agreement # 899368

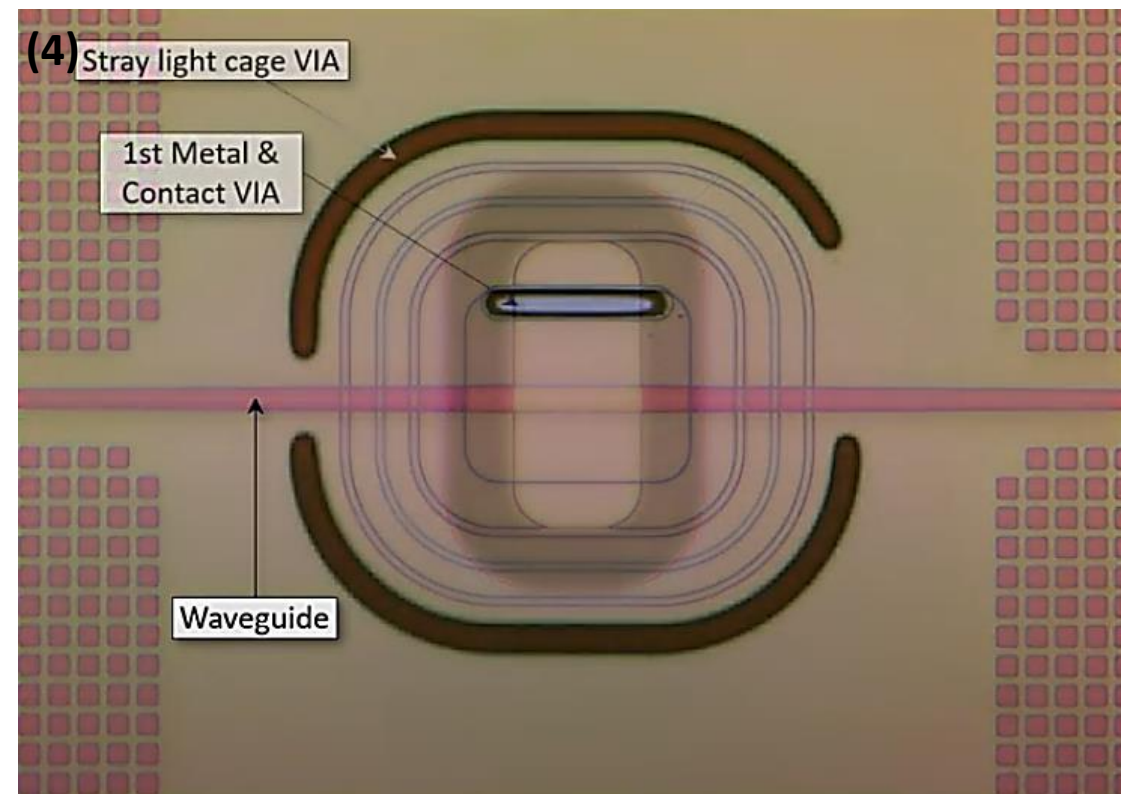
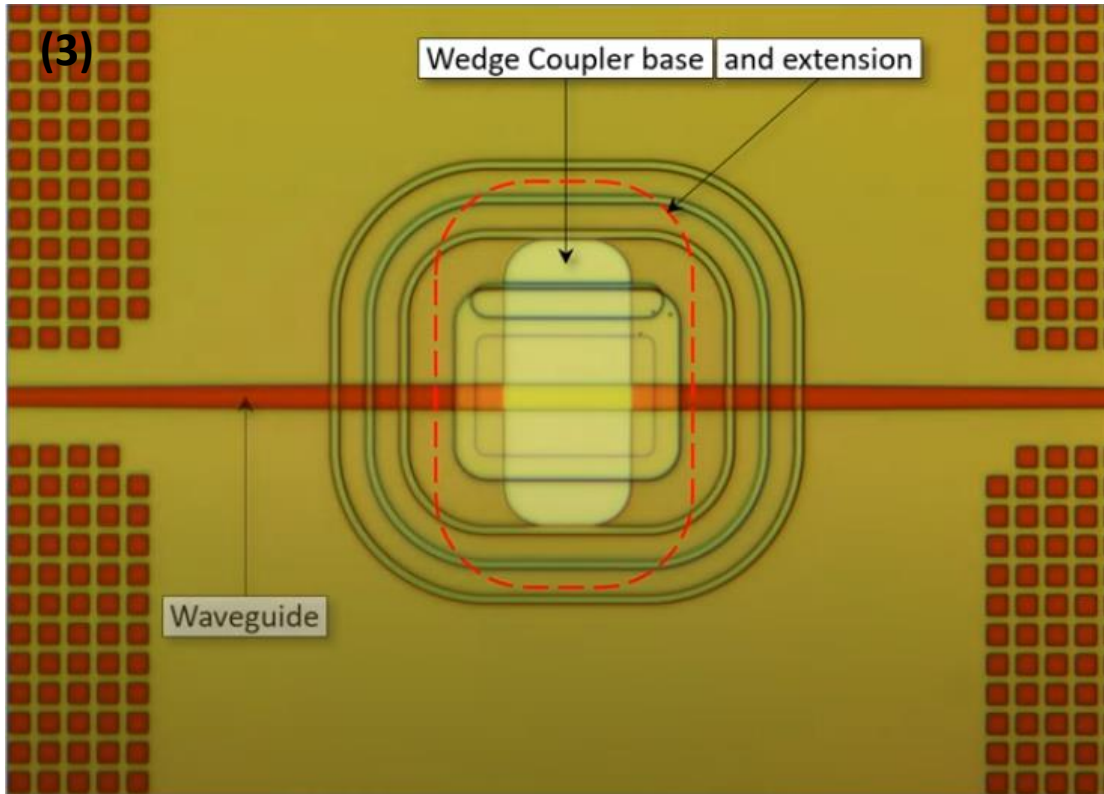




- Litho and implants on Silicon wafers
- SPAD and diode formation
 - N-on-p (p-epi) junction type
 - FBK “RGB” SPAD and SiPM technology

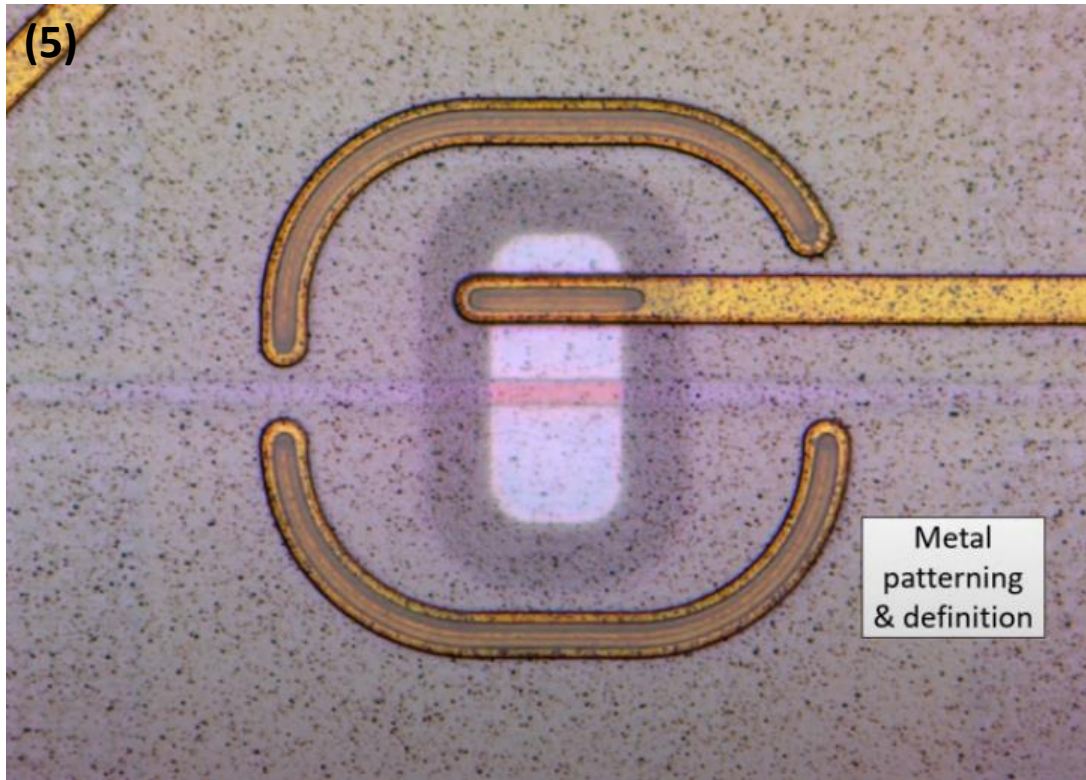
- Wedge coupling region definition
- smaller than SPAD region
 - To compensate for E-field edge effects
 - To compensate for partial light leakage

Fabrication of integrated chip: PIC+SPADs

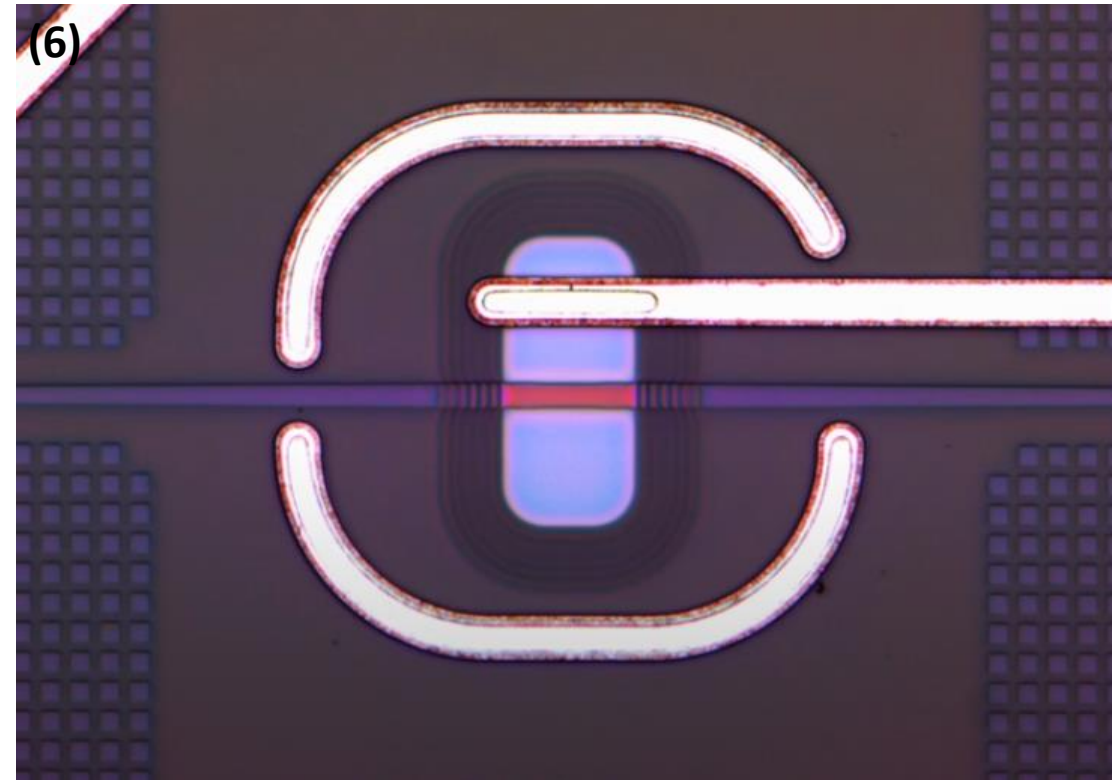


- Deposit BEOL: SiN (or SiON)
- Litho and Waveguide (WG) definition
 - Larger footprint on coupling region

- VIA opening and 1st metal deposition:
 - Electric contacts
- Creation of light cage structures
 - Stray-light and optical crosstalk mitigation

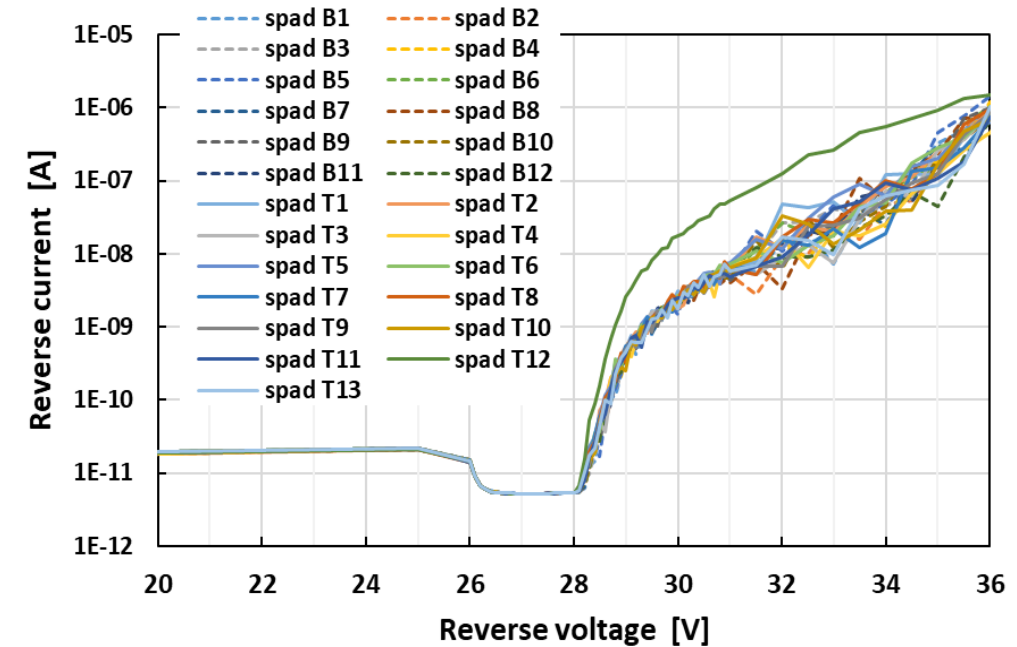
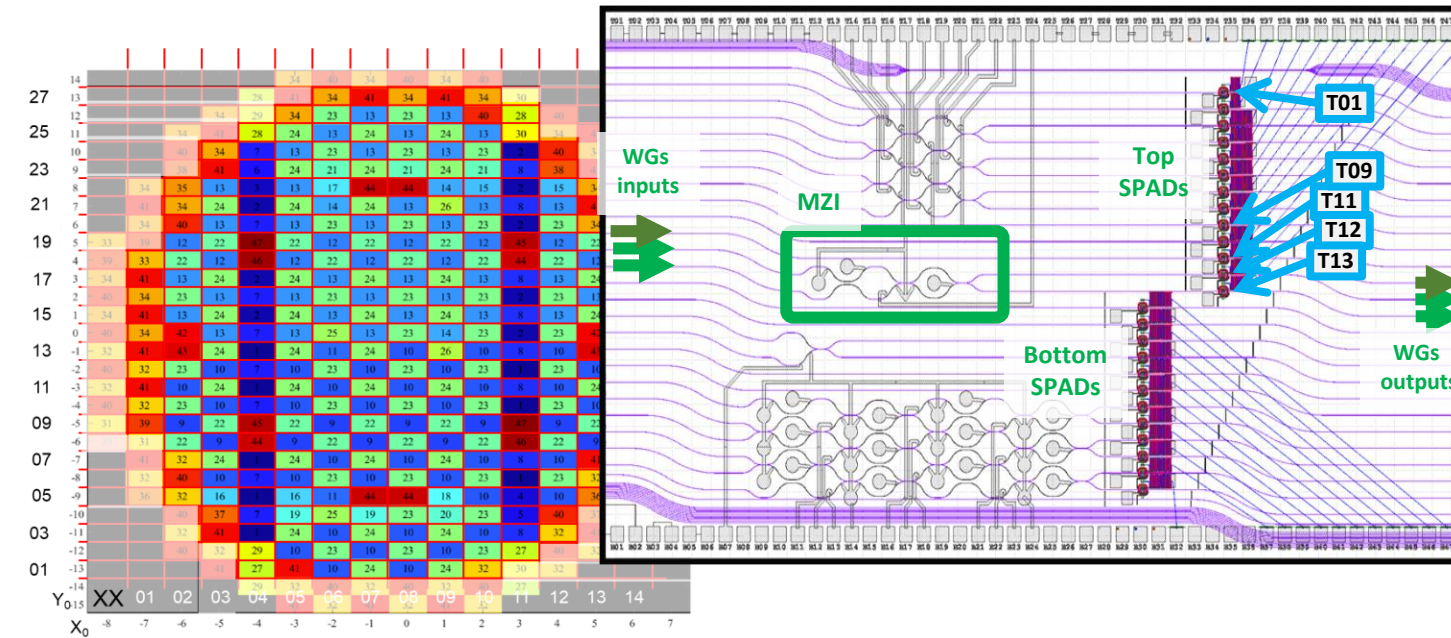


- 2nd metal deposition
- Patterning and definition



- Overglass deposition
- PAD openings

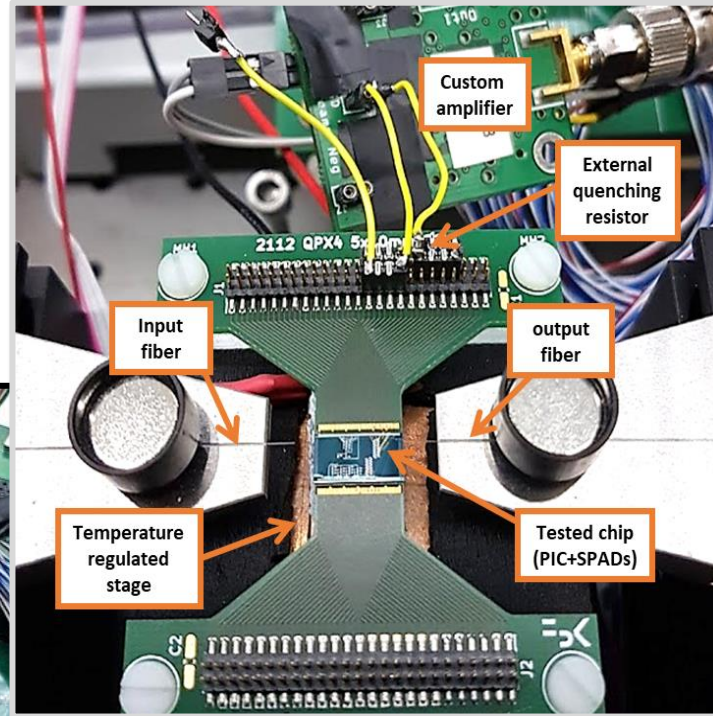
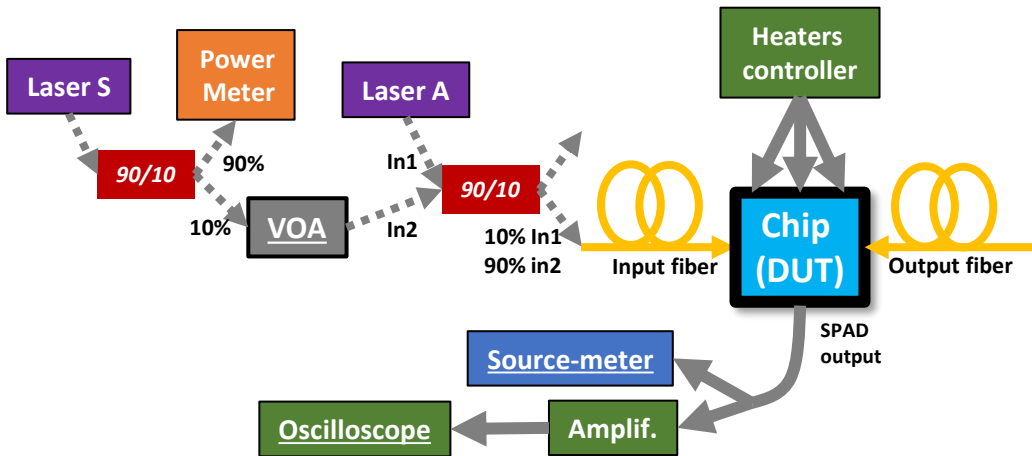
Test chip #1: wafer-level electrical characterization



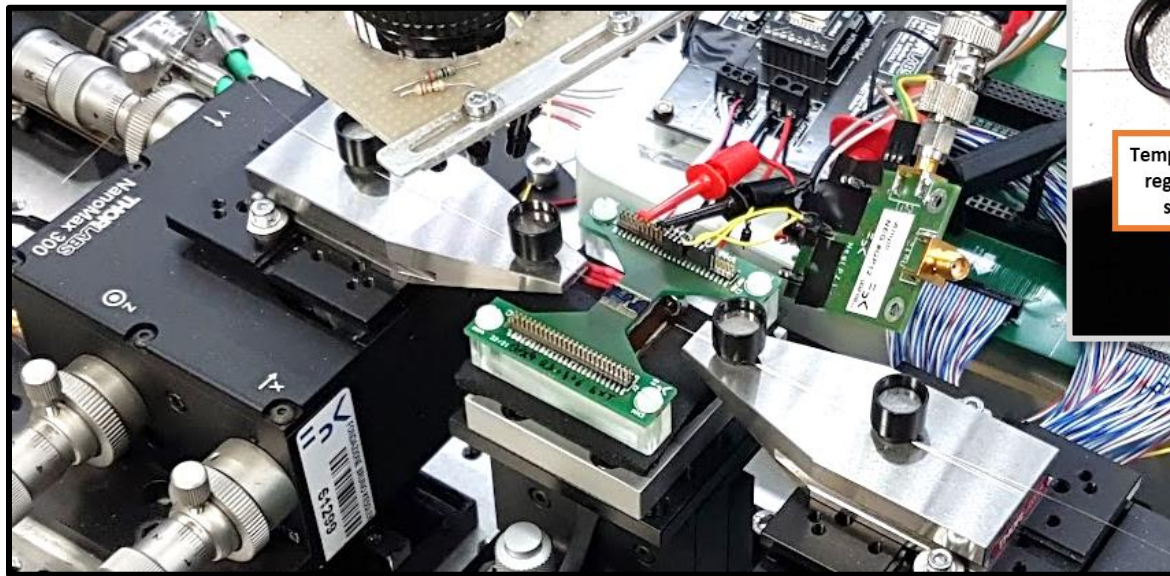
➤ Wafer level electrical testing → measurements of fw and reverse IV curves of diodes and SPADs

- 6" wafers → Several chip tested
- Good uniformity in breakdown voltage in the SPADs (~28V)
- *Relatively low yield because of process-related issue* → *to be solved in future production*

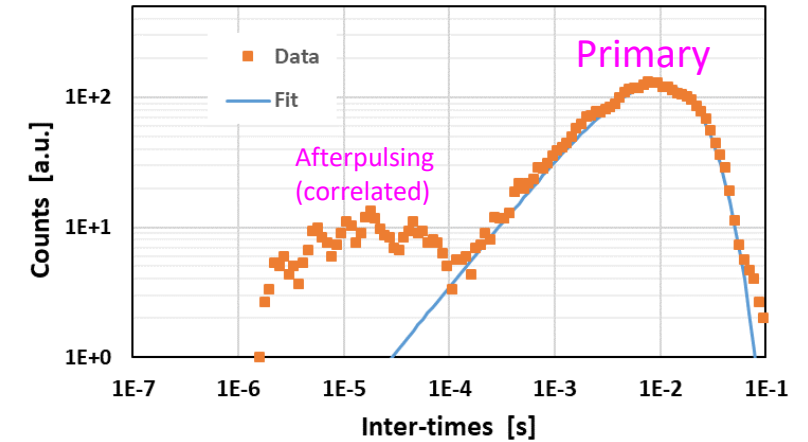
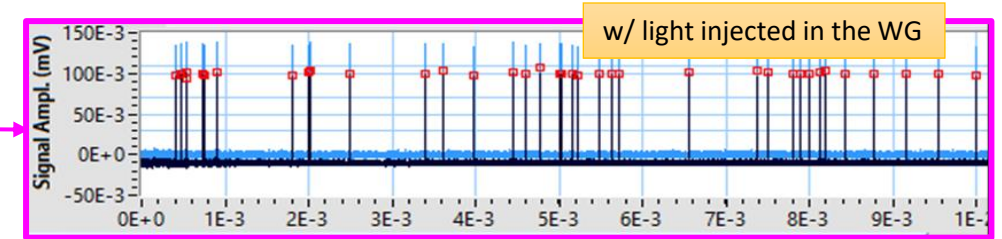
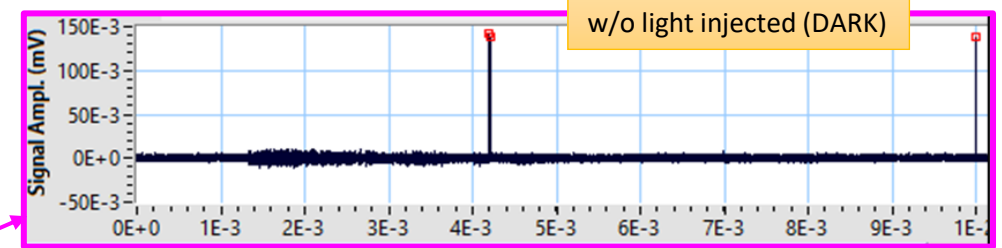
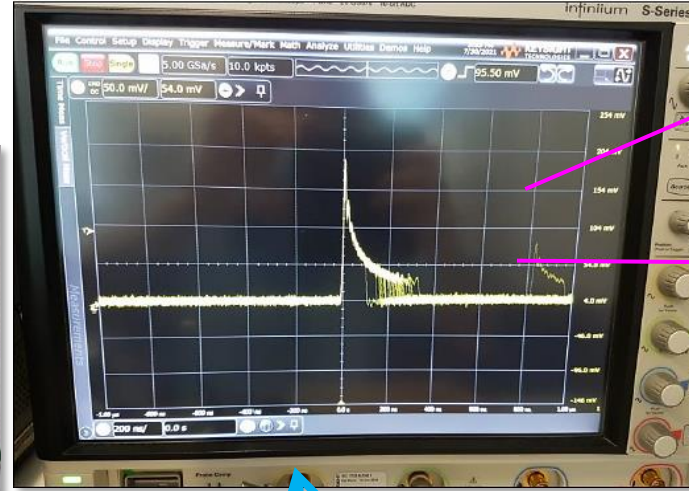
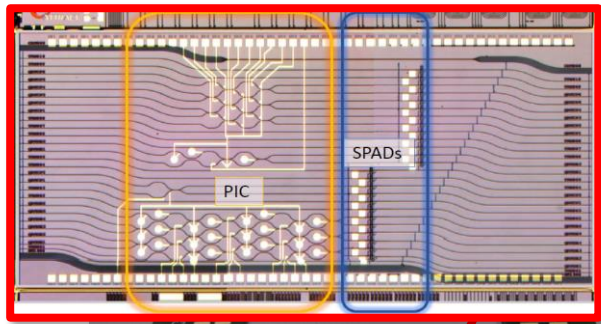
Test chip #1: Photonic/optoelectronic characterization



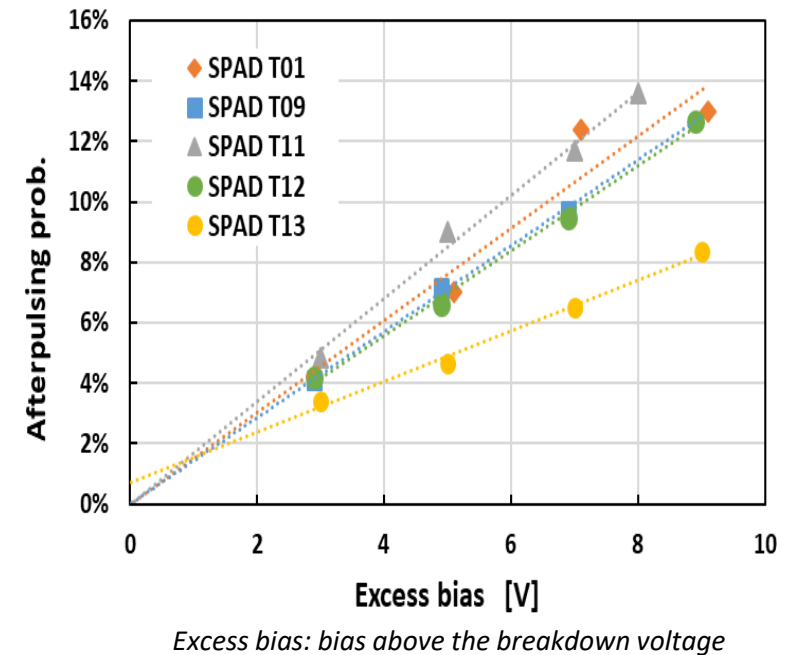
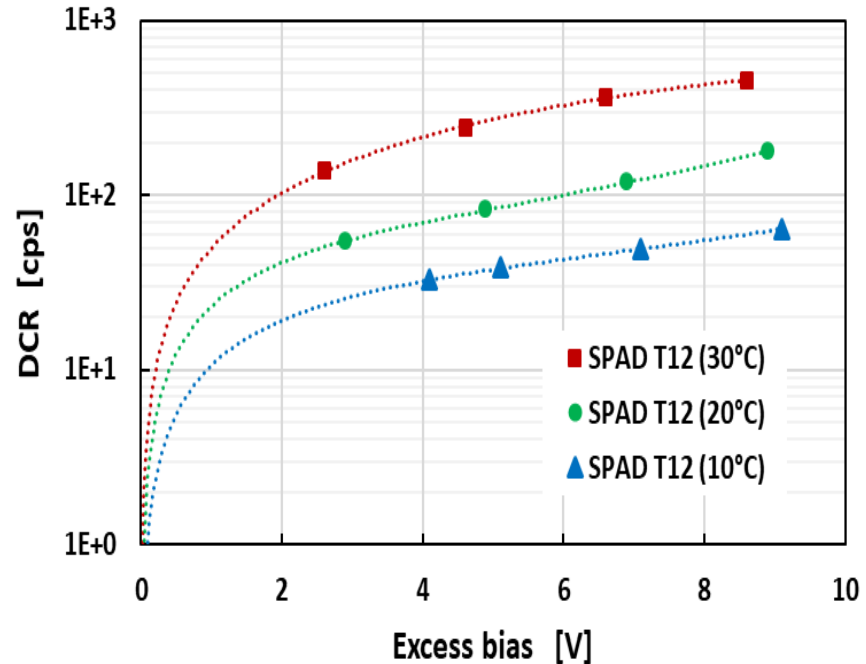
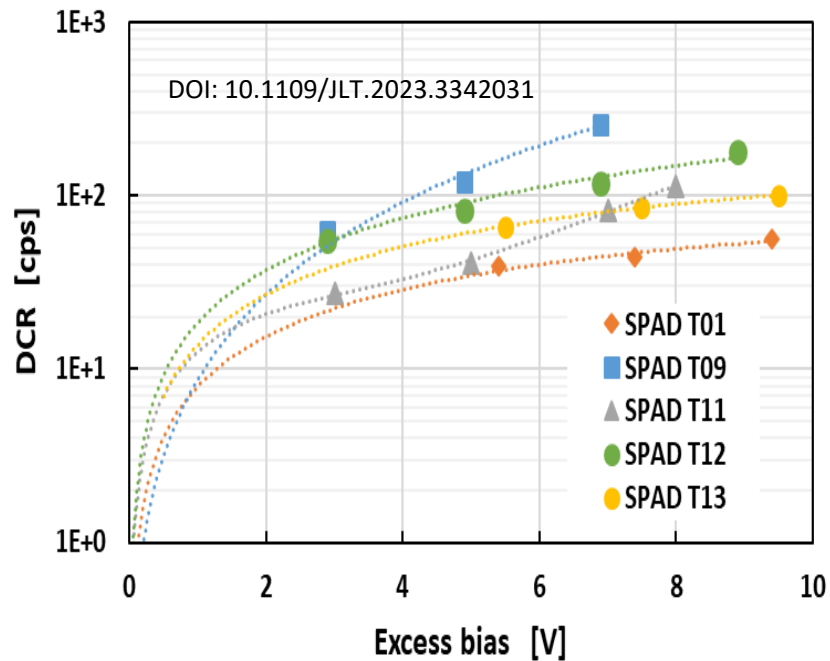
- Source laser (850 nm)
- Alignment laser
- Multiple variable optical attenuators:
 - Pre-calibration: with high light intensity
 - Use: to single-ph. Level
- *TEC cooling*
- SPADs:
 - External quench. resistors
 - Custom sig. amplifier



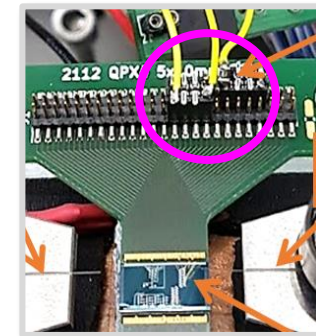
Pulse-counting performance



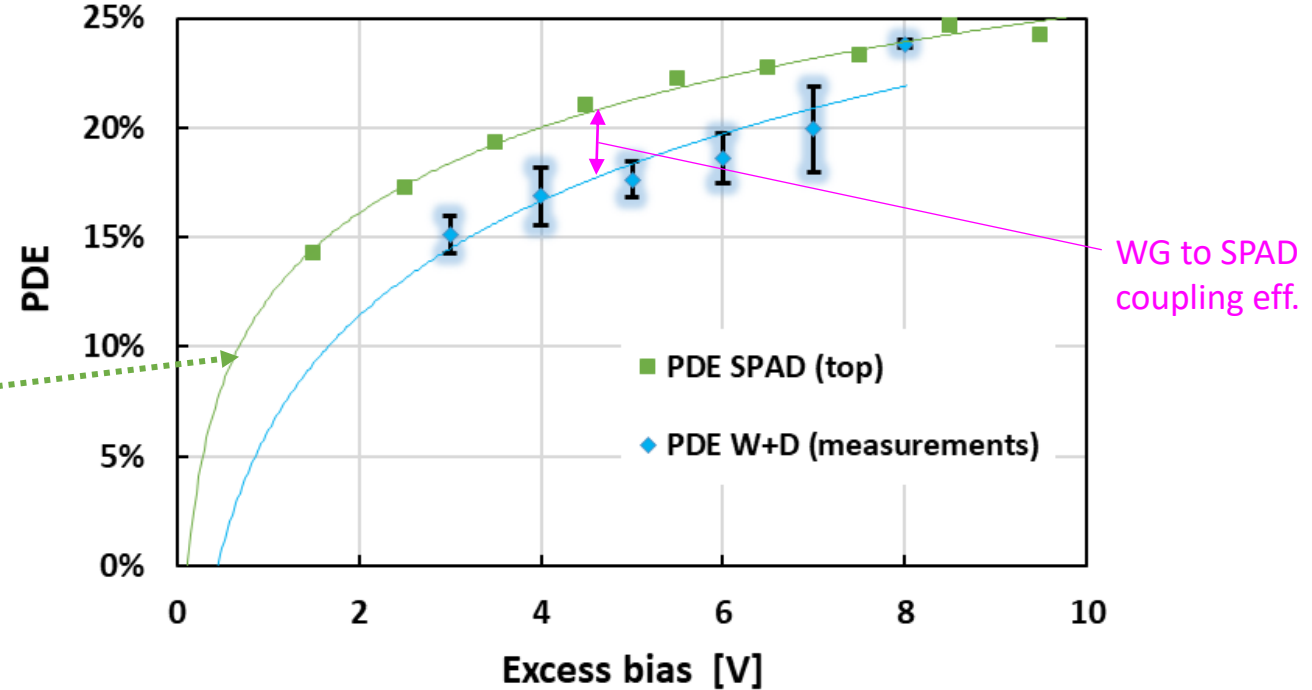
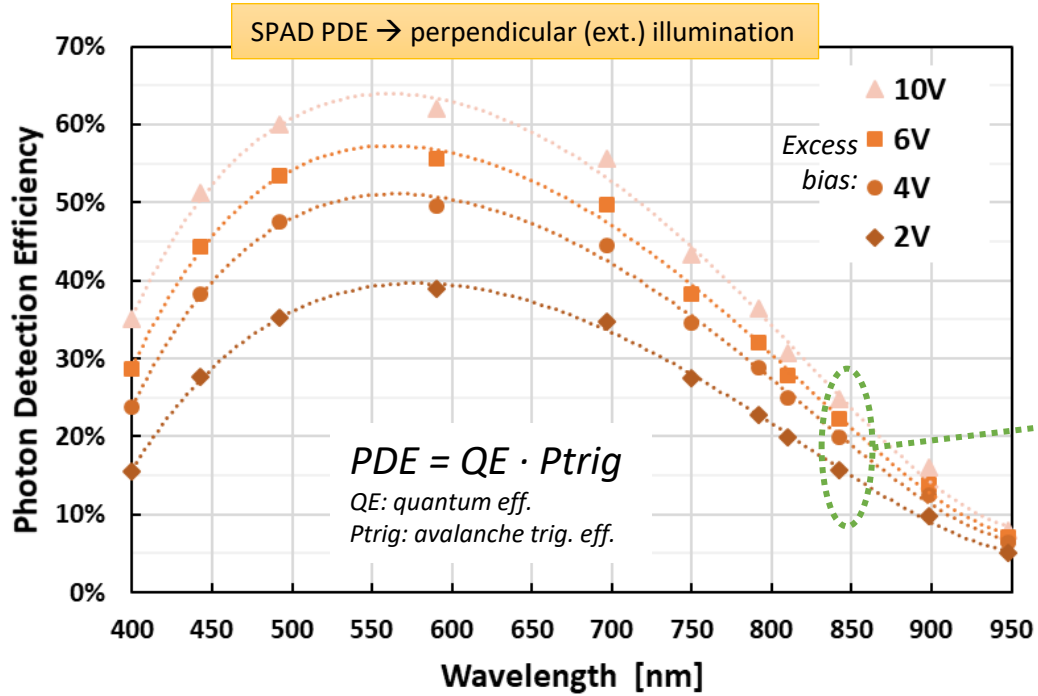
- SPAD pulse rate: proportional to the injected light intensity
- Inter-times between pulses → exponential statistics
→ extraction of primary and correlated events



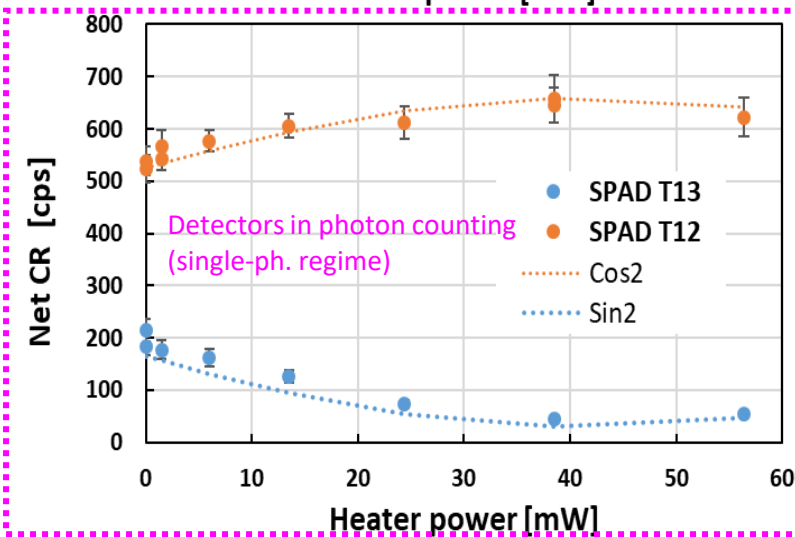
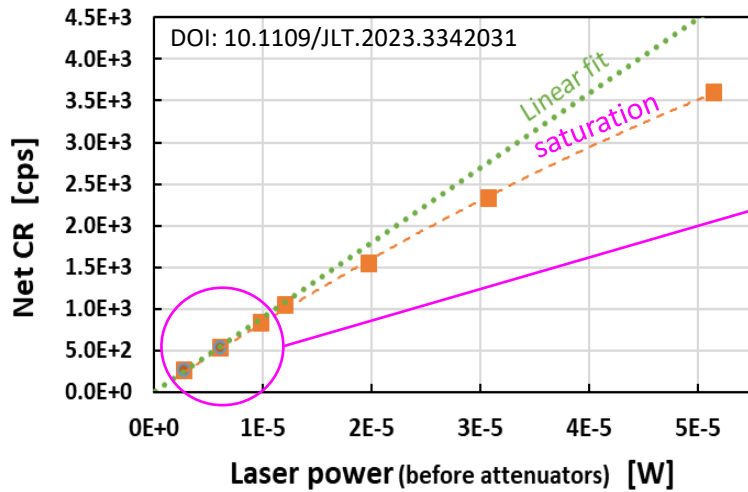
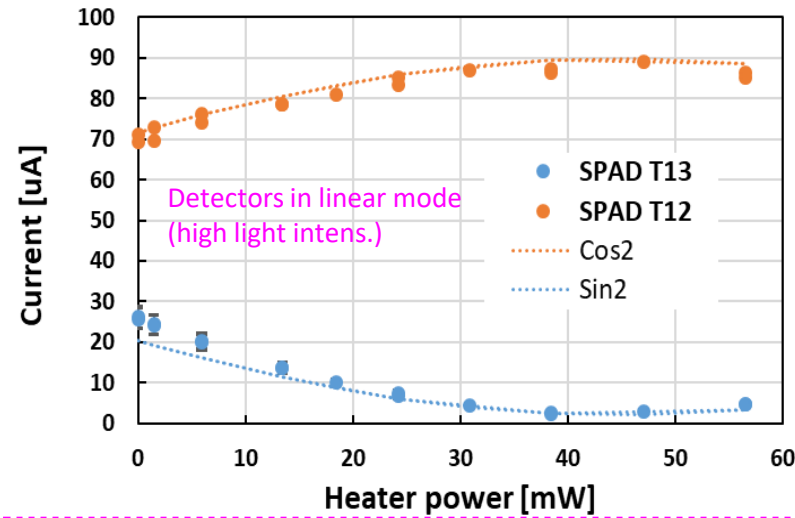
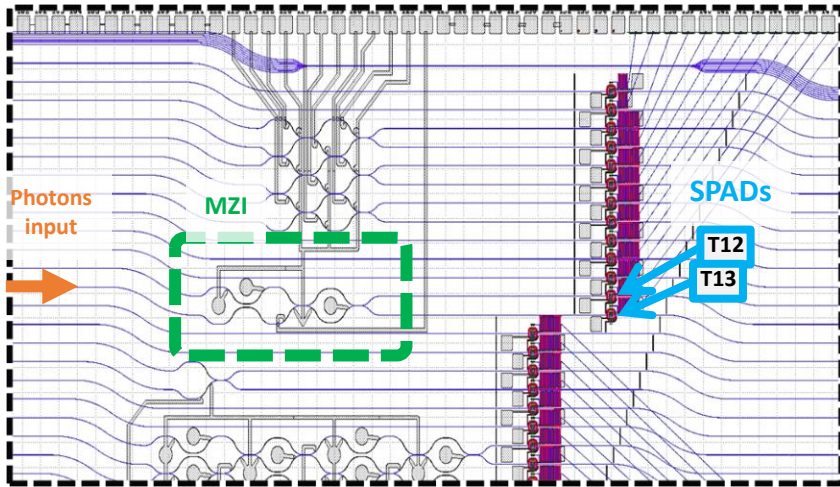
- Dark count rate (primary noise)
 - ~100 counts per second (cps) @ 20°C
 - in line with state-of-the-art Si-SPAD (commercial product)
- Temperature dependence: DCR halved about every 10°C
- Afterpulsing relatively high → *because of the external quenching (not optimized)(not the operative conditions)*



Detection efficiency and light-coupling efficiency



- Si-SPAD measurement with external light:
 - PDE peaked in the green wavelength region → ~20% ÷ 25 % at 850nm
- laser light injected into WG + detection by SPAD:
 - Detection efficiency= ~17% ÷ 20 % at 850nm → WG-to-SPAD coupling efficiency= ~ 76% ÷ 85%

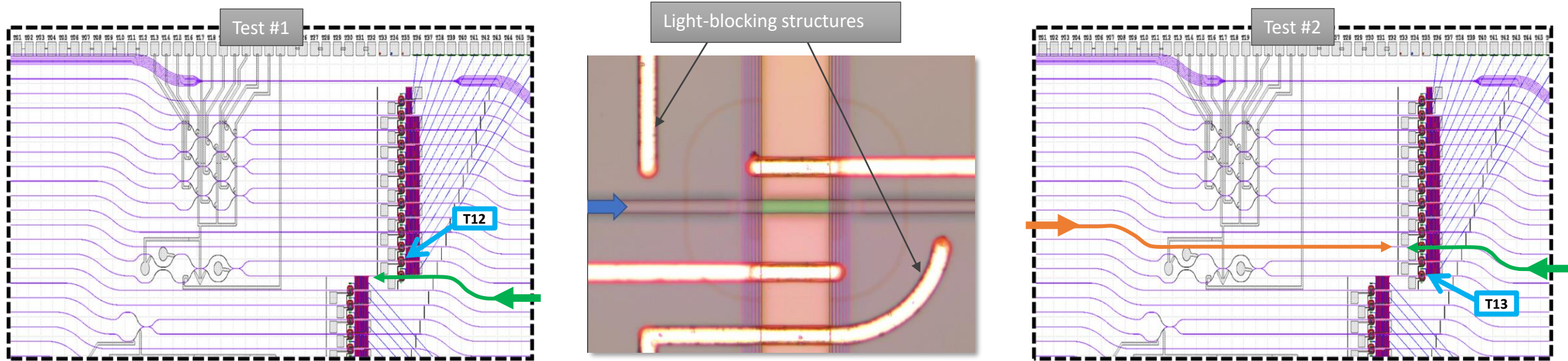


➤ Direct test of photon manipulation and detection

- Single photons injected.
- MZI (driven by heaters)
- 2 SPAD detectors

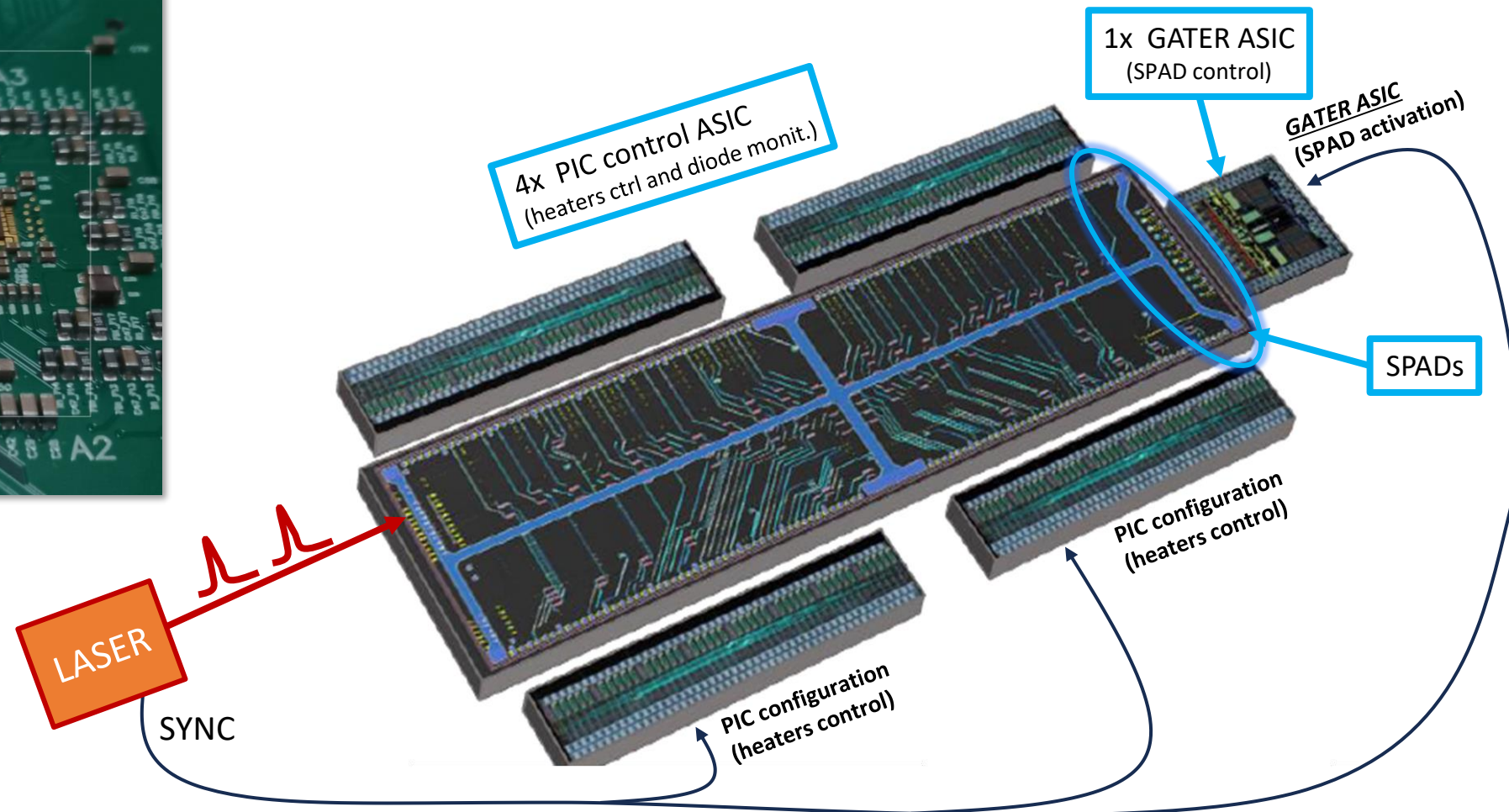
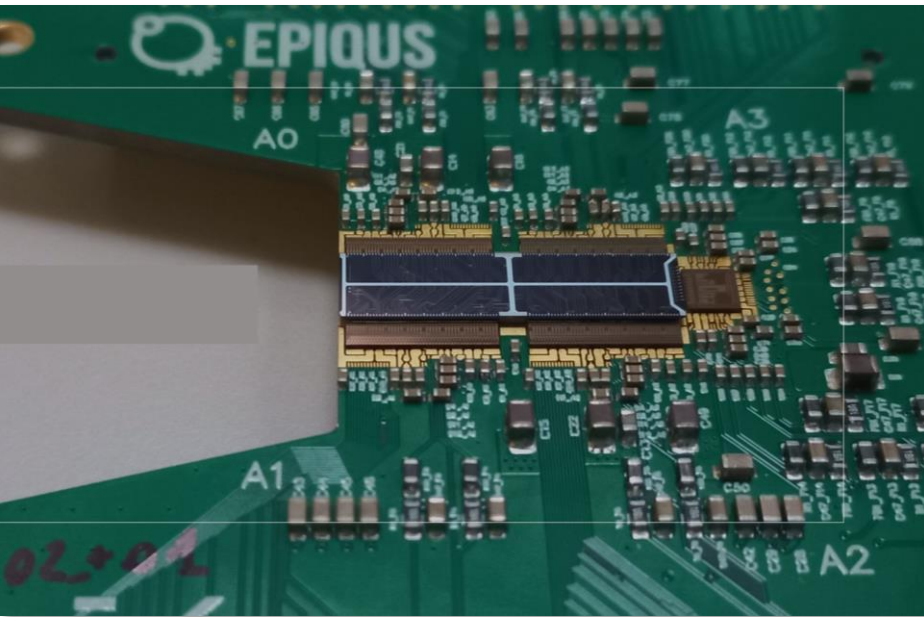
Procedure:

1. Selection of non-saturated power range
2. Heater power modulation
3. Count rate measurements (in the 2 SPADs)
4. Good agreement: photon counting behavior vs linear-mode behavior



- Test #1: light from the right side WG associated to SPAD T13, monitoring SPAD T12.
 - we estimated a detection efficiency of about **0.04%**.
- Test #2: light from left or right side of WG associated to SPAD T11, monitoring SPAD T13
 - detection efficiency around **0.03%** (first case) and **0.16%** (second case).
- Minor stray-light → thanks to light blocking structures

Next: complete quantum simulator (EPIQUS project)



- *Periodic PIC and SPAD configuration/enabling, synchronous with input light pulses*

- New **CMOS compatible top-down evanescent approach for monolithic electronic-photonic integration**
 - ✓ material all CMOS compatible,
 - ✓ it does not require alignments, butt coupling, or two waveguides made in different materials,
 - ✓ it can be operated at room temperature,
 - ✓ design of the SPADs does not have particular restrictions.
- Fabricated the first PICs with integrated silicon SPADs:
 - moderately low dark count rate
 - Good photon detection probability (improvable in future runs)
 - SPADs well appropriate for short gating pulses in a photonic quantum simulator.
 - system detection efficiency (i.e. PIC+SPAD), being between 17% and 20%
 - Waveguide-to-detectors coupling efficiency ~ 80%.
- Direct test of photon manipulation and detection:
 - Modulation of photons propagation between two adjacent waveguides and detection.
- Promising technology for future developments at FBK.
- *Future runs: improvement of detection efficient (light trapping)*

Silicon SPAD monolithically integrated with SiON-based photonic circuit

Fabio Acerbi, Martino Bernard, Alberto Gola, Georg Pucker, Mher Ghulinyan

Fondazione Bruno Kessler (FBK), Center for Sensors and Devices, Trento, Italy.

acerbi@fbk.eu